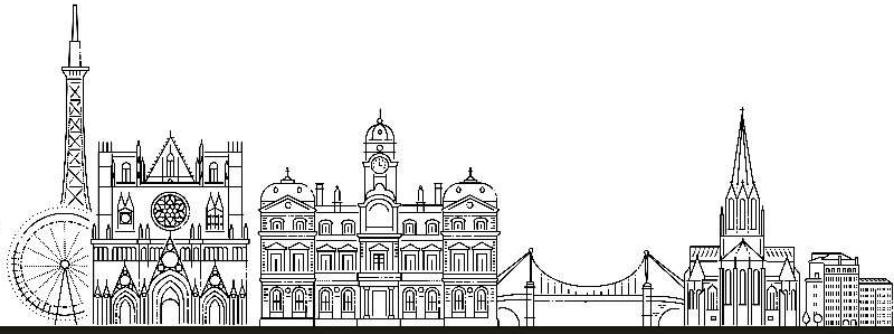


ECerS
SUMMER
SCHOOL



Advanced Characterization Techniques

29-30 JUNE 2023 • INSA LYON • FRANCE

PROGRAMME

Day 1 - Thursday 29th June 2023

08 h 30 – 09 h 10: Breakfast

09 h 10 – 09 h 20 : Welcome-Opening

09 h 20 – 09 h 30: EcerS-JECS Trust

09 h 30 – 09 h 45: YCN

09 h 45 – 10 h 45 : Low voltage SEM S. Christiansens, Fraunhofer-Institut für Keramische Technologien und Systeme IKTS

10 h 45 Coffee Break

11 h 00 – 12 h 00 : FIB/Sample preparation T. Salminen, Microscopy Center, Tampere

University of Technology

12 h 00 Lunch

13 h 30 – 14 h 30 : Image processing R. Podor, CEA Marcoule

14 h 30 Coffee Break

14 h 45 – 16 h 15 : Demo

16 h 15 Break

16 h 30 – 18 h 00 : Demo

19 h 30: Gala Diner

Day 2 - Friday 30th June 2023

8 h00 – 8h40 : Breakfast

8 h 40 – 9 h 40 : X-ray tomography X-ray tomography - L. Mancini, Zavod za gradbeništvo Slovenije

09 h 45 – 10 h 45 : Transmission Electron Microscopy - D. Rafaja, Institute of Materials Science, TU Bergakademie Freiberg

10 h 45 Coffee Break

11 h 00 – 12 h 00 : EBSD K. Marquardt, Imperial college London

12 h 00 Lunch

13 h 30 – 14 h 30 : SEM in situ testing - S. Wang, Imperial college London

14 h 30 Coffee Break

14 h 45 – 16 h 15 : Demo

16 h 15 Break

16 h 30 – 18 h 00 : Demo

List of demos:

- SEM low voltage
- EBSD
- In situ heating in ESEM
- FIB (tomography reconstruction)
- In situ tests in TEM (heating or nanocompression)
- TEM: imaging/diffraction
- X-ray tomography

